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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/605,449	09/30/2003	Dennis R. Conti	BUR920030050US1	2448	
26679 DRIGGS. HOO	7590 03/29/2007 GG & FRY CO. L.P.A.		EXAM	EXAMINER	
38500 CHARD			HOLLINGTON, JERMELE M		
DEPT. IBU WILLOUGHB	Y HILLS, OH 44094		ART UNIT	PAPER NUMBER	
	1111225, 011 11031		2829		
SHORTENED STATUTOR	RY PERIOD OF RESPONSE	MAIL DATE	DELIVER	DELIVERY MODE	
3 MO	ONTHS	03/29/2007	I	PAPER	

Please find below and/or attached an Office communication concerning this application or proceeding.

If NO period for reply is specified above, the maximum statutory period will apply and will expire 6 MONTHS from the mailing date of this communication.

t			<u> </u>			
	Application No.	Applicant(s)				
· _	10/605,449	CONTI ET AL.				
Office Action Summary	Examiner	Art Unit				
	Jermele M. Hollington	2829				
The MAILING DATE of this communication app Period for Reply	pears on the cover sheet with the	correspondence address	•			
A SHORTENED STATUTORY PERIOD FOR REPL	Y IS SET TO EXPIRE 3 MONTH	H(S) OR THIRTY (30) DAY	'S			
<ul> <li>WHICHEVER IS LONGER, FROM THE MAILING D</li> <li>Extensions of time may be available under the provisions of 37 CFR 1.1 after SIX (6) MONTHS from the mailing date of this communication.</li> <li>If NO period for reply is specified above, the maximum statutory period</li> <li>Failure to reply within the set or extended period for reply will, by statute Any reply received by the Office later than three months after the mailin earned patent term adjustment. See 37 CFR 1.704(b).</li> </ul>	ATE OF THIS COMMUNICATION  136(a). In no event, however, may a reply be will apply and will expire SIX (6) MONTHS from the come application to become ABANDOR	ON. timely filed om the mailing date of this communical NED (35 U.S.C. § 133).				
Status						
1) Responsive to communication(s) filed on 01 h	lovember 2006.					
2a) This action is <b>FINAL</b> . 2b) ☑ This	s action is non-final.	•				
3) Since this application is in condition for allowa	ance except for formal matters, p	rosecution as to the merits	is is			
closed in accordance with the practice under i	Ex parte Quayle, 1935 C.D. 11,	453 O.G. 213.				
Disposition of Claims	•					
4)⊠ Claim(s) <u>1-12</u> is/are pending in the application	۱.					
4a) Of the above claim(s) is/are withdrawn from consideration.						
5)⊠ Claim(s) <u>1-6</u> is/are allowed.						
6)⊠ Claim(s) <u>7-12</u> is/are rejected.						
7) Claim(s) is/are objected to.	L. C. Samenat					
8) Claim(s) are subject to restriction and/o	or election requirement.		,			
Application Papers						
9) The specification is objected to by the Examine	er.	•				
10) The drawing(s) filed on is/are: a) accepted or b) objected to by the Examiner.						
Applicant may not request that any objection to the						
Replacement drawing sheet(s) including the correct						
11) The oath or declaration is objected to by the E	xaminer. Note the attached Office	ce Action or form PTO-152	•			
Priority under 35 U.S.C. § 119		•	•			
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of:	n priority under 35 U.S.C. § 119	(a)-(d) or (f).				
1. Certified copies of the priority documen	its have been received.					
2. Certified copies of the priority documen	its have been received in Applica	ation No				
<ol><li>Copies of the certified copies of the price</li></ol>		ived in this National Stage				
application from the International Burea						
* See the attached detailed Office action for a lis	t of the certified copies not recei	ved.				
Attachment(s)						
1) Notice of References Cited (PTO-892)	4) Interview Summa Paper No(s)/Mail					
<ul> <li>2) Notice of Draftsperson's Patent Drawing Review (PTO-948)</li> <li>3) Information Disclosure Statement(s) (PTO/SB/08)</li> </ul>	5) Notice of Informa					
Paper No(s)/Mail Date	6) Other:					

Application/Control Number: 10/605,449

Art Unit: 2829

### **DETAILED ACTION**

## Response to Arguments

1. Applicant's arguments, see "Arguments", filed November 1, 2006, with respect to claims 1-6 have been fully considered and are persuasive. The 35 U.S.C. 102 rejections of claims 1-6 have been withdrawn.

Regarding claims 7-10, the examiner believes the rejection is valid base on MPEP 2114.

MPEP 2114 states that while features of an apparatus may be recited either structurally or functionally, claims directed to an apparatus must be distinguished from the prior art in terms of structure rather than function alone. In other words, a recitation directed to the manner in which a claimed apparatus is intended to be used does not distinguished the claimed apparatus from the prior art.

# Claim Rejections - 35 USC § 102

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 3. Claims 7-10 are rejected under 35 U.S.C. 102(b) as being anticipated by Iino et al (5568054).

Regarding claims 7-8, Iino et al disclose [see Fig. 6] controlling the burning in of at least one I/C chip (IC chip on wafer W) in a burn in tool (inspection section 12), wherein said tool (12) has a device (probe card 20) for mounting each chip (IC on wafer W) to be burned in, and a

Application/Control Number: 10/605,449

Art Unit: 2829

power source (power source 40) to supply electrical current to burn in each chip (IC on wafer W), comprising the steps of: continuously monitoring [via measuring section 41] at least one electrical value input to each chip (on wafer W) wherein the current value is maintain at or below a given value [see col. 2, lines 9-30, col. 5, lines 3-63, col. 6, lines 29-37 and col. 7, line 47-col. 8, line 13].

Regarding claim 9, Iino et al disclose [see Fig. 6] at least one electrical value input to each chip (on wafer W) wherein the power value is maintain at or below a given value [see col. 2, lines 9-30, col. 5, lines 3-63, col. 6, lines 29-37 and col. 7, line 47-col. 8, line 13].

Regarding claim 10, Iino et al disclose a monitor (measuring section 41) to continuously monitor the temperature value of each chip (W) being burned in and wherein the voltage is varied to maintain the temperature value of each device at a given value [see col. 2, lines 9-30, col. 5, lines 3-63, col. 6, lines 29-37 and col. 7, line 47-col. 8, line 13].

4. Claims 7, and 10-12 are rejected under 35 U.S.C. 102(b) as being anticipated by Hamilton (5911897).

Regarding claim 7, Hamilton discloses a burn in tool (burn in board 10) for burning in at least one I/C chip (IC chip 12) comprising: a structure (heat sink assembly 24) for mounting each chip (12) to be burned in; a power source (V REF) to supply electrical current to burn in each chip (12); a structure (sensor housing 44) for continuously monitoring at least one electrical value input to each chip (12) selected from the group of current, voltage and power, and a structure to vary the voltage to maintain at least one of the values at or below a given value.

Application/Control Number: 10/605,449

Art Unit: 2829

Regarding claim 10 Hamilton discloses a monitor (temperature sensor 48) to continuously monitor the temperature value of each chip (12) being burned in and wherein the voltage is varied to maintain the temperature value of each device at a given value.

Regarding claim 11, Hamilton discloses a heat sink (heat sink 34) is in contact with each device (24).

Regarding claim 12, Hamilton discloses the tool (10) has a heat sink (heat sink 34) and temperature monitor (48) for each device (24) and each heat sink (34) has means (48) to control the temperature of the heat sink (34), and the temperature control means (22) is varied to maintain the temperature value of each device (24) at a given value.

### Conclusion

- 5. Claims 1-6 are allowed.
- 6. The following is a statement of reasons for the indication of allowable subject matter: regarding claim 1, the reason for the allowance is due to a method of controlling the burning in of at least one IC chip in a burn in tool having a monitor for each chip to continuously monitor the temperature value of each chip. Since claims 2-6 depend from claim 1, they also have allowable subject matter.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Jermele M. Hollington whose telephone number is (571) 272-1960. The examiner can normally be reached on M-F (9:00-4:00 EST) First Friday Off.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Ha Nguyen can be reached on (571) 272-1678. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Art Unit: 2829

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Jermele M. Hollington Primary Examiner

Art Unit 2829

JMH March 27, 2007